

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	117	(feature near10 critical adj dimension).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 08:17
L2	64	(feature near10 critical adj dimension).clm. and substrate.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 08:18
L3	420174	(feature near10 critical adj dimension).clm. and substrate.clm. sand semiconductor.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 08:18
L4	21	(feature near10 critical adj dimension).clm. and substrate.clm. and semiconductor.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 08:18
L5	7	(feature near10 critical adj dimension).clm. near10 substrate.clm. and semiconductor.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 08:18
L6	3	(feature near10 critical adj dimension).clm. near10 substrate.clm. near10 semiconductor.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 08:18